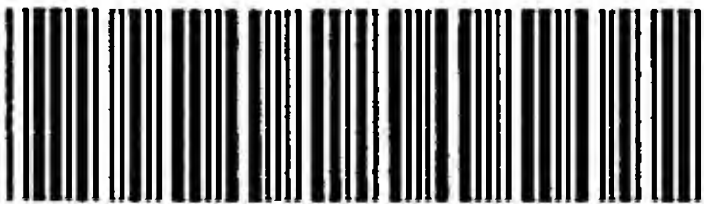
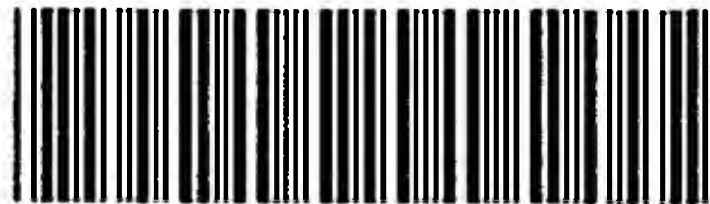


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/605,602	WANG, SUNG-FEI	
	Examiner	Art Unit	
	Sing P. Chan	1734	

SEARCHED			
Class	Subclass	Date	Examiner
156	60, 250, 256, 267, 307.3, 308.2	10/27/2005	SPC
156	309.6	10/27/2005	SPC
165	72-74, 79	10/27/2005	SPC
165	80.1-80.3	10/27/2005	SPC
165	185	10/27/2005	SPC
165	DIG515	10/27/2005	SPC
D13	179	10/27/2005	SPC
257	706, 707	10/27/2005	SPC
361	707, 710	10/27/2005	SPC
361	717-720	10/27/2005	SPC
361	600, 679	10/27/2005	SPC
361	688, 704	10/27/2005	SPC
257	704, 712	10/27/2005	SPC

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
156	60, 250	10/27/2005	SPC
156	256, 267	10/27/2005	SPC
156	307.3	10/27/2005	SPC
156/308.2, 309.6; 165/72-74, 79, 80.1-80.3, 185, DIG 515		10/27/2005	SPC

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Text and image search on EAST	10/27/2005	SPC
Inventor search on EAST and PALM on Wang Sung-Fei	10/27/2005	SPC
PGPUB Text search, Interference Searched	10/27/2005	SPC

Search Notes (continued)

Application/Control No.

10/605,602

Examiner

Sing P. Chan

Applicant(s)/Patent under
Reexamination

WANG, SUNG-FEI

Art Unit

1734

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
D13	179	10/27/2005	SPC
257	704, 706	10/27/2005	SPC
257	707	10/27/2005	SPC
361/707, 710, 717-720, 600, 679, 688, 704		10/27/2005	SPC

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR